ABSTRACT OF THE DISCLOSURE

AN INSPECTION SYSTEM

An inspection system for three dimensional inspection of minute objects on a substrate, the system comprising:

a calibration module to calibrate an inspection angle for capturing an oblique image of the objects, the calibration of the inspection angle being performed by using one object as a reference;

at least one image capturor to capture a first image of the objects, and to capture an oblique image of the objects; and

an image processor to determine the position of the objects using the first image, and the height of the objects using the oblique image and the first image;

wherein if the height of an object is not within a predetermined criteria it is classified as defective and the position of the defective object is identified.

FIG. 2